SDAS232A - DECEMBER 1983 - REVISED JANUARY 1995

	OR NT PACKAG (TOP VIEW)		AGE
OF [	10	24	Voc
	2	23	1Q
2D [	3	22	2Q
3D [	4	21	3Q
4D [	5	20	4Q
5D [	6	19	5Q
6D [	7	18	6Q
7D [	8	17	7Q
8D [	9	16	8Q
9D [	10	- 1	9Q
CLR [	11	14	PRE
GND [	12	13	LE
	OE [ 1D [ 2D [ 3D [ 4D [ 5D [ 6D [ 7D [ 8D [ 9D [ CLR [	OE [ 1 1 1 2 2 2 1 3 3 3 1 4 4 4 5 5 5 1 6 6 6 6 7 7 7 5 1 8 8 5 1 9 9 5 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1	(TOP VIEW)  OE [ 1

This 9-bit bus-interface D-type latch features 3-state outputs designed specifically for driving

highly capacitive or relatively low-impedance loads. It is particularly suitable for implementing buffer registers, I/O ports, bidirectional bus drivers, and working registers.

The nine latches are transparent D-type latches with noninverting data (D) inputs.

A buffered output-enable  $(\overline{OE})$  input places the nine outputs in either a normal logic state (high or low logic levels) or a high-impedance state. In the high-impedance state, the outputs neither load nor drive the bus lines significantly. The high-impedance state and increased drive provide the capability to drive bus lines without interface or pullup components.

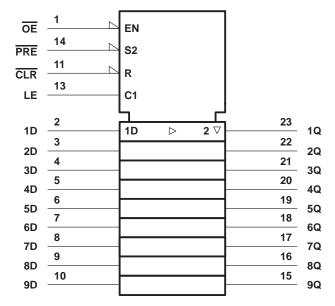
OE does not affect the internal operation of the latches. Previously stored data can be retained or new data can be entered while the outputs are off.

The SN74ALS843 is characterized for operation from 0°C to 70°C.

#### **FUNCTION TABLE**

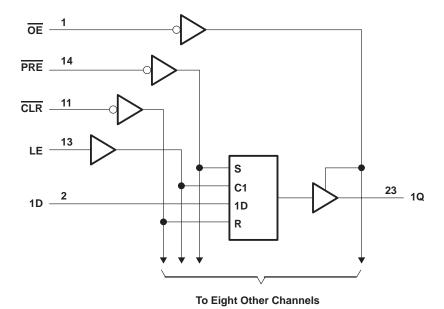
		INPUTS	;		OUTPUT
PRE	CLR	OE	LE	D	Q
L	Х	L	Х	Χ	Н
Н	L	L	X	Χ	L
Н	Н	L	Н	L	L
Н	Н	L	Н	Н	Н
Н	Н	L	L	Χ	Q <sub>0</sub>
Х	Χ	Н	Χ	Χ	Z

## logic symbol†



<sup>&</sup>lt;sup>†</sup> This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

## logic diagram (positive logic)



TEXAS INSTRUMENTS
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### absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage, V <sub>CC</sub>		7 V
Input voltage, V <sub>I</sub>		7 V
Voltage applied to a disabled 3-state output		
Operating free-air temperature range, T <sub>A</sub>		. 0°C to 70°C
Storage temperature range	–6	35°C to 150°C

### recommended operating conditions

			MIN	NOM	MAX	UNIT
VCC	Supply voltage		4.5	5	5.5	V
VIH	High-level input voltage		2			V
V <sub>IL</sub>	Low-level input voltage				0.8	V
ІОН	High-level output current				-2.6	mA
l <sub>OL</sub>	Low-level output current				24	mA
		CLR or PRE low	35			no
t <sub>W</sub> Pulse duration	ruise duration	LE high	20			ns
t <sub>su</sub>	Setup time, data before LE↓		10			ns
th	Hold time, data after LE↓		5			ns
TA	Operating free-air temperature		0		70	°C

# electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS		MIN	TYP‡	MAX	UNIT
VIK	V <sub>CC</sub> = 4.5 V,	I <sub>I</sub> = -18 mA			-1.2	V
Vari	$V_{CC} = 4.5 \text{ V to } 5.5 \text{ V},$	$I_{OH} = -0.4 \text{ mA}$	V <sub>CC</sub> -2			V
VOH	$V_{CC} = 4.5 V,$	$I_{OH} = -2.6 \text{ mA}$	2.4	3.2		V
Ve	V== -4.5.V	I <sub>OL</sub> = 12 mA		0.25	0.4	V
VOL	$V_{CC} = 4.5 V$	I <sub>OL</sub> = 24 mA		0.35	0.5	]
l <sub>OZH</sub>	V <sub>CC</sub> = 5.5 V,	V <sub>O</sub> = 2.7 V			20	μΑ
lozL	V <sub>CC</sub> = 5.5 V,	V <sub>O</sub> = 0.4 V			-20	μΑ
lj	$V_{CC} = 5.5 V,$	V <sub>I</sub> = 7 V			0.1	mA
IIH	$V_{CC} = 5.5 V,$	V <sub>I</sub> = 2.7 V			20	μΑ
I <sub>IL</sub>	$V_{CC} = 5.5 V,$	V <sub>I</sub> = 0.4 V			-0.1	mA
ΙΟ§	V <sub>CC</sub> = 5.5 V,	V <sub>O</sub> = 2.25 V	-30		-112	mA
		Outputs high		21	36	
ICC	$V_{CC} = 5.5 V$	Outputs low		41	67	mA
		Outputs disabled		25	42	

<sup>‡</sup> All typical values are at  $V_{CC} = 5 \text{ V}$ ,  $T_A = 25^{\circ}\text{C}$ .



<sup>†</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

<sup>§</sup> The output conditions have been chosen to produce a current that closely approximates one half of the true short-circuit output current, IOS.

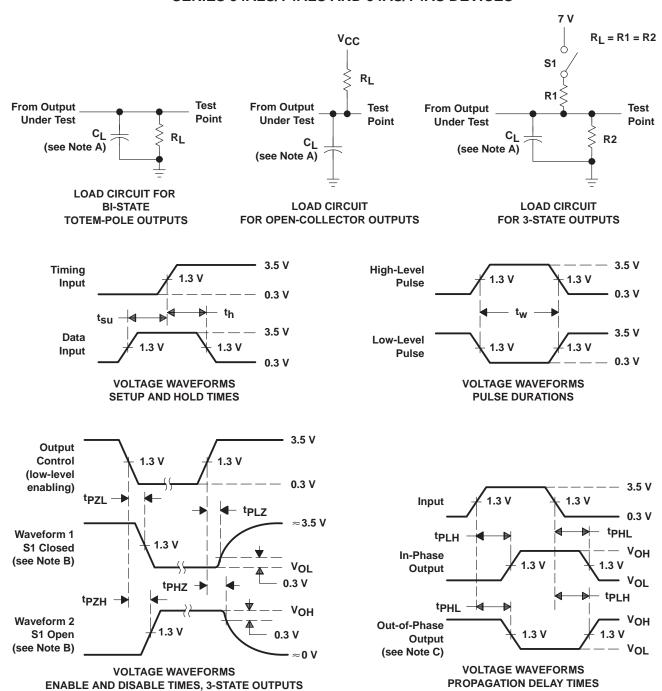
# **SN74ALS843** 9-BIT BUS-INTERFACE D-TYPE LATCH WITH 3-STATE OUTPUTS SDAS232A - DECEMBER 1983 - REVISED JANUARY 1995

## switching characteristics (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	$\begin{aligned} & \text{V}_{\text{CC}} = 4.5 \text{ V to } 5.5 \text{ V,} \\ & \text{C}_{\text{L}} = 50 \text{ pF,} \\ & \text{R1} = 500 \ \Omega, \\ & \text{R2} = 500 \ \Omega, \\ & \text{T}_{\text{A}} = \text{MIN to MAX}^{\dagger} \end{aligned}$		TO $R1 = 500 \Omega$ (OUTPUT) $R2 = 500 \Omega$		UNIT
			MIN	MAX			
<sup>t</sup> PLH	D		2	13	ns		
<sup>t</sup> PHL	Ь	Q	4	18	115		
t <sub>PLH</sub>	LE		5	21	ns		
<sup>t</sup> PHL		Q	8	26	115		
t <sub>PLH</sub>	PRE	Q	5	22	ns		
<sup>t</sup> PHL	CLR		6	23	115		
<sup>t</sup> PZH	ŌĒ		2	12			
t <sub>PZL</sub>	)E	Q	4	14	ns		
<sup>t</sup> PHZ	ŌĒ	Q	2	10	ns		
t <sub>PLZ</sub>	)E	3	2	12	1115		

<sup>†</sup> For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

### PARAMETER MEASUREMENT INFORMATION SERIES 54ALS/74ALS AND 54AS/74AS DEVICES



NOTES: A. C<sub>L</sub> includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. When measuring propagation delay items of 3-state outputs, switch S1 is open.
- D. All input pulses have the following characteristics: PRR  $\leq$  1 MHz,  $t_r = t_f = 2$  ns, duty cycle = 50%.
- E. The outputs are measured one at a time with one transition per measurement.

Figure 1. Load Circuits and Voltage Waveforms



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